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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, SPI, UART/USART, USB
Peripherals	DMA, POR, PWM, WDT
Number of I/O	51
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	2.4V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f070rbt6

List of tables

3.5.4 Low-power modes

The STM32F070CB/RB/C6/F6 microcontrollers support three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop mode**

  Stop mode achieves very low power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low power mode.

  The device can be woken up from Stop mode by any of the EXTI lines. The EXTI line source can be one of the 16 external lines and RTC.

- **Standby mode**

  The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the RTC domain and Standby circuitry.

  The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pins, or an RTC event occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

3.6 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-32 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example on failure of an indirectly used external crystal, resonator or oscillator).

Several prescalers allow the application to configure the frequency of the AHB and the APB domains. The maximum frequency of the AHB and the APB domains is 48 MHz.

3.8 Direct memory access controller (DMA)

The 5-channel general-purpose DMA manages memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers.

The DMA supports circular buffer management, removing the need for user code intervention when the controller reaches the end of the buffer.

Each channel is connected to dedicated hardware DMA requests, with support for software trigger on each channel. Configuration is made by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI, I2C, USART, all TIMx timers (except TIM14) and ADC.

3.9 Interrupts and events

3.9.1 Nested vectored interrupt controller (NVIC)

The STM32F0xx family embeds a nested vectored interrupt controller able to handle up to 32 maskable interrupt channels (not including the 16 interrupt lines of Cortex®-M0) and 4 priority levels.

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail-chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimal interrupt latency.

3.9.2 Extended interrupt/event controller (EXTI)

The extended interrupt/event controller consists of 32 edge detector lines used to generate interrupt/event requests and wake-up the system. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the internal clock period. Up to 51 GPIOs can be connected to the 16 external interrupt lines.

3.10 Analog to digital converter (ADC)

The 12-bit analog to digital converter has up to 16 external and two internal (temperature sensor, voltage reference measurement) channels and performs conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Table 2. Temperature sensor calibration values

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C (± 5 °C), V_{DDA}= 3.3 V (± 10 mV)	0x1FFF F7B8 - 0x1FFF F7B9

3.10.2 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC. V_{REFINT} is internally connected to the ADC_IN17 input channel. The precise voltage of V_{REFINT} is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

Table 3. Internal voltage reference calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at a temperature of 30 °C (± 5 °C), V_{DDA}= 3.3 V (± 10 mV)	0x1FFF F7BA - 0x1FFF F7BB

can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

3.11.5 System window watchdog (WWDG)

The system window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the APB clock (PCLK). It has an early warning interrupt capability and the counter can be frozen in debug mode.

3.11.6 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0
- Programmable clock source (HCLK or HCLK/8)

3.12 Real-time clock (RTC)

The RTC is an independent BCD timer/counter. Its main features are the following:

- Calendar with subseconds, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Automatic correction for 28, 29 (leap year), 30, and 31 day of the month.
- Programmable alarm with wake up from Stop and Standby mode capability.
- Periodic wakeup unit with programmable resolution and period.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize the RTC with a master clock.
- Digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy.
- Tow anti-tamper detection pins with programmable filter. The MCU can be woken up from Stop and Standby modes on tamper event detection.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be woken up from Stop and Standby modes on timestamp event detection.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.

The RTC clock sources can be:

- A 32.768 kHz external crystal
- A resonator or oscillator
- The internal low-power RC oscillator (typical frequency of 40 kHz)
- The high-speed external clock divided by 32

3.13 Inter-integrated circuit interfaces (I^2C)

Up to two I2C interfaces (I2C1 and I2C2) can operate in multimaster or slave modes. Both can support Standard mode (up to 100 kbit/s) or Fast mode (up to 400 kbit/s). I2C1 also supports Fast Mode Plus (up to 1 Mbit/s), with 20 mA output drive.

Both support 7-bit and 10-bit addressing modes, multiple 7-bit slave addresses (two addresses, one with configurable mask). They also include programmable analog and digital noise filters.

Table 5. Comparison of I2C analog and digital filters

-	Analog filter	Digital filter
Pulse width of suppressed spikes	≥ 50 ns	Programmable length from 1 to 15 I2C peripheral clocks
Benefits	Available in Stop mode	1. Extra filtering capability vs. standard requirements. 2. Stable length
Drawbacks	Variations depending on temperature, voltage, process	-

In addition, I2C1 provides hardware support for SMBUS 2.0 and PMBUS 1.1: ARP capability, Host notify protocol, hardware CRC (PEC) generation/verification, timeouts verifications and ALERT protocol management.

The I2C interfaces can be served by the DMA controller.

Refer to *Table 6* for the differences between I2C1 and I2C2.

Table 6. STM32F070CB/RB/C6/F6 I^2C implementation(1)

I2C features	I2C1	I2C2(2)
7-bit addressing mode	X	X
10-bit addressing mode	X	X
Standard mode (up to 100 kbit/s)	X	X
Fast mode (up to 400 kbit/s)	X	X
Fast Mode Plus (up to 1 Mbit/s), with 20mA output drive I/Os	X	-
Independent clock	X	-
SMBus	X	-
Wakeup from STOP	-	-

1. X = supported.
2. Only available on STM32F070xB devices.

3.14 Universal synchronous/asynchronous receiver/transmitter (USART)

The device embeds up to four universal synchronous/asynchronous receivers/transmitters that communicate at speeds of up to 6 Mbit/s.

Table 7 gives an overview of features as implemented on the available USART interfaces. All USART interfaces can be served by the DMA controller.

Table 7. STM32F70x0 USART implementation(1)

USART modes/ features	STM32F070x6		STM32F070xB		
	USART1	USART2	USART1 USART2	USART3	USART4
Hardware flow control for modem	X	X	X	X	X
Continuous communication using DMA	X	X	X	X	-
Multiprocessor communication	X	X	X	X	X
Synchronous mode	X	X	X	X	X
Smartcard mode	-	-	-	-	-
Single-wire Half-duplex communication	X	X	X	X	X
IrDA SIR ENDEC block	-	-	-	-	-
LIN mode	-	-	-	-	-
Dual clock domain and wakeup from Stop mode	-	-	-	-	-
Receiver timeout interrupt	X	-	X	-	-
Modbus communication	-	-	-	-	-
Auto baud rate detection (supported modes)	4	-	4	-	-
Driver Enable	X	X	X	X	X
USART data length	7, 8 and 9 bits				

1. **X = supported.**

3.15 Serial peripheral interface (SPI)

Up to two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

SPI1 and SPI2 are identical and implement the set of features shown in the following table.

Figure 5. TSSOP20 20-pin package pinout (top view)

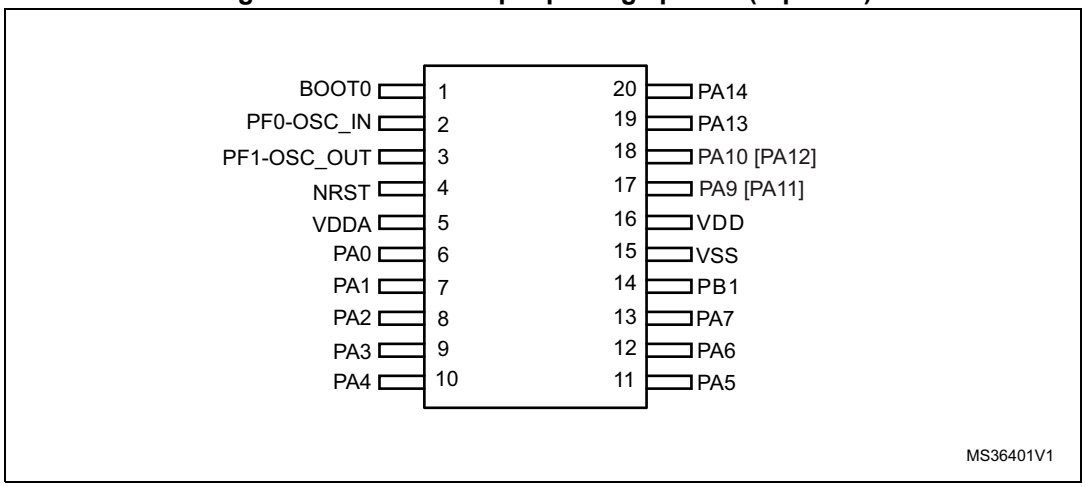


Table 9. Legend/abbreviations used in the pinout table

Name		Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type		S	Supply pin
		I	Input only pin
		I/O	Input / output pin
I/O structure		FT	5 V tolerant I/O
		FTf	5 V tolerant I/O, FM+ capable
		TTa	3.3 V tolerant I/O directly connected to ADC
		TC	Standard 3.3 V I/O
		B	Dedicated BOOT0 pin
		RST	Bidirectional reset pin with embedded weak pull-up resistor
Notes		Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset.	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers	
	Additional functions	Functions directly selected/enabled through peripheral registers	

Table 10. STM32F070xB/6 pin definitions

Pin numbers			Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	LQFP48	TSSOP20					Alternate functions	Additional functions
1	1	-	VDD	S	-	-	Digital power supply	
2	2	-	PC13	I/O	TC	(1) (2)	-	WKUP2, RTC_TAMP1, RTC_TS, RTC_OUT
3	3	-	PC14-OSC32_IN (PC14)	I/O	TC	(1) (2)	-	OSC32_IN
4	4	-	PC15-OSC32_OUT (PC15)	I/O	TC	(1) (2)	-	OSC32_OUT
5	5	2	PF0-OSC_IN (PF0)	I/O	FT	-	I2C1_SDA(3)	OSC_IN
6	6	3	PF1-OSC_OUT (PF1)	I/O	FT	-	I2C1_SCL(3)	OSC_OUT
7	7	4	NRST	I/O	RST	-	Device reset input / internal reset output (active low)	
8	-	-	PC0	I/O	TTa	-	EVENTOUT	ADC_IN10
9	-	-	PC1	I/O	TTa	-	EVENTOUT	ADC_IN11
10	-	-	PC2	I/O	TTa	-	SPI2_MISO, EVENTOUT	ADC_IN12
11	-	-	PC3	I/O	TTa	-	SPI2_MOSI, EVENTOUT	ADC_IN13
12	8	-	VSSA	S	-	-	Analog ground	
13	9	5	VDDA	S	-	-	Analog power supply	
14	10	6	PA0	I/O	TTa	(4)	USART2_CTS, USART4_TX	RTC_ TAMP2, WKUP1, ADC_IN0,
15	11	7	PA1	I/O	TTa	(4)	USART2_RTS, TIM15_CH1N, USART4_RX, EVENTOUT	ADC_IN1
16	12	8	PA2	I/O	TTa	(4)	USART2_TX, TIM15_CH1	ADC_IN2, WKUP4
17	13	9	PA3	I/O	TTa	(4)	USART2_RX, TIM15_CH2	ADC_IN3
18	-	-	VSS	S	-	-	Ground	
19	-	-	VDD	S	-	-	Digital power supply	
20	14	10	PA4	I/O	TTa	-	SPI1_NSS, TIM14_CH1, USART2_CK, USB_NOE(3)	ADC_IN4
21	15	11	PA5	I/O	TTa	-	SPI1_SCK	ADC_IN5

Table 11. Alternate functions selected through GPIOA_AFR registers for port A

Pin name	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
PA0	-	USART2_CTS	-	-	USART4_TX(1)	-	-	-
PA1	EVENTOUT	USART2_RTS	-	-	USART4_RX(1)	TIM15_CH1N(1)	-	-
PA2	TIM15_CH1(1)	USART2_TX	-	-	-	-	-	-
PA3	TIM15_CH2(1)	USART2_RX	-	-	-	-	-	-
PA4	SPI1_NSS	USART2_CK	USB_NOE(2)	-	TIM14_CH1	-	-	-
PA5	SPI1_SCK	-	-	-	-	-	-	-
PA6	SPI1_MISO	TIM3_CH1	TIM1_BKIN	-	USART3_CTS(1)	TIM16_CH1	EVENTOUT	-
PA7	SPI1_MOSI	TIM3_CH2	TIM1_CH1N	-	TIM14_CH1	TIM17_CH1	EVENTOUT	-
PA8	MCO	USART1_CK	TIM1_CH1	EVENTOUT	-	-	-	-
PA9	TIM15_BKIN(1)	USART1_TX	TIM1_CH2	-	I2C1_SCL (2)	-	-	-
PA10	TIM17_BKIN	USART1_RX	TIM1_CH3	-	I2C1_SDA (2)	-	-	-
PA11	EVENTOUT	USART1_CTS	TIM1_CH4	-	-	-	-	-
PA12	EVENTOUT	USART1_RTS	TIM1_ETR	-	-	-	-	-
PA13	SWDIO	IR_OUT	USB_NOE	-	-	-	-	-
PA14	SWCLK	USART2_TX	-	-	-	-	-	-
PA15	SPI1_NSS	USART2_RX	-	EVENTOUT	USART4_RTS(1)	-	-	-

1. Available on STM32F070CB/RB devices only.
2. Available on STM32F070C6/F6 devices only.

Table 16. STM32F070CB/RB/C6/F6 peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4000 7400 - 0x4000 7FFF	3 KB	Reserved
	0x4000 7000 - 0x4000 73FF	1 KB	PWR
	0x4000 6C00 - 0x4000 6FFF	1 KB	Reserved
	0x4000 6400 - 0x4000 67FF	2 KB	Reserved
	0x4000 6000 - 0x4000 63FF	1 KB	USB RAM
	0x4000 5800 - 0x4000 5BFF	1 KB	I2C2(1)
	0x4000 5400 - 0x4000 57FF	1 KB	I2C1
	0x4000 5000 - 0x4000 53FF	3 KB	Reserved
	0x4000 4C00 - 0x4000 4FFF	1 KB	USART4(1)
	0x4000 4800 - 0x4000 4BFF	1 KB	USART3(1)
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 3C00 - 0x4000 43FF	2 KB	Reserved
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2(1)
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	Reserved
	0x4000 2000 - 0x4000 23FF	1 KB	TIM14
	0x4000 1800 - 0x4000 1FFF	2 KB	Reserved
	0x4000 1400 - 0x4000 17FF	1 KB	TIM7
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
	0x4000 0400 - 0x4000 07FF	1 KB	TIM3
	0x4000 0000 - 0x4000 03FF	1 KB	Reserved

1. Available on STM32F070CB/RB devices only.

Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO.

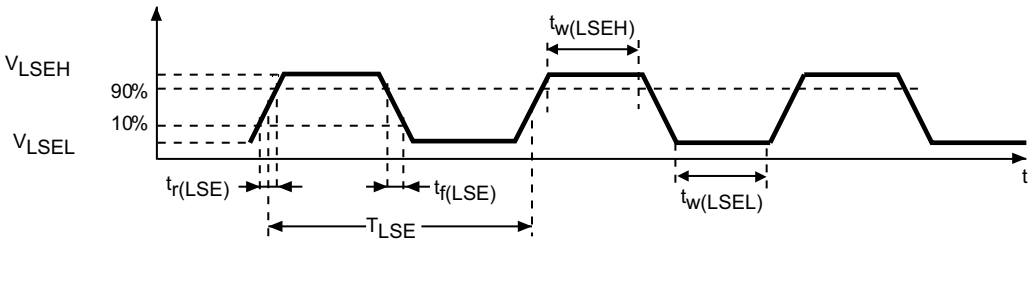
The external clock signal has to respect the I/O characteristics in *Section 6.3.14*. However, the recommended clock input waveform is shown in *Figure 12*.

Table 31. Low-speed external user clock characteristics

Symbol	Parameter(1)	Min	Typ	Max	Unit
f_{LSE_ext}	User external clock source frequency	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	0.7 V_{DDIOx}	-	V_{DDIOx}	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS}	-	0.3 V_{DDIOx}	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time	-	-	50	

1. Guaranteed by design, not tested in production.

Figure 12. Low-speed external clock source AC timing diagram



High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 32 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in *Table 32*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 32. HSE oscillator characteristics

Symbol	Parameter	Conditions(1)	Min(2)	Typ	Max(2)	Unit
f_{OSC_IN}	Oscillator frequency	-	4	8	32	MHz
R_F	Feedback resistor	-	-	200	-	kΩ

Table 39. Flash memory endurance and data retention

Symbol	Parameter	Conditions	Min(1)	Unit
N_{END}	Endurance	T_A = -40 to +85 °C	1	kcycle
t_{RET}	Data retention	1 kcycle(2) at T_A = 85 °C	20	Years

1. Data based on characterization results, not tested in production.
2. Cycling performed over the whole temperature range.

6.3.11 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports). the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB**: A Burst of Fast Transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in *Table 40*. They are based on the EMS levels and classes defined in application note AN1709.

Table 40. EMS characteristics

Symbol	Parameter	Conditions	Level/ Class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3V, LQFP48, T_A = +25 °C, f_{HCLK} = 48 MHz, conforming to IEC 61000-4-2	3B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD} = 3.3V, LQFP48, T_A = +25°C, f_{HCLK} = 48 MHz, conforming to IEC 61000-4-4	4B

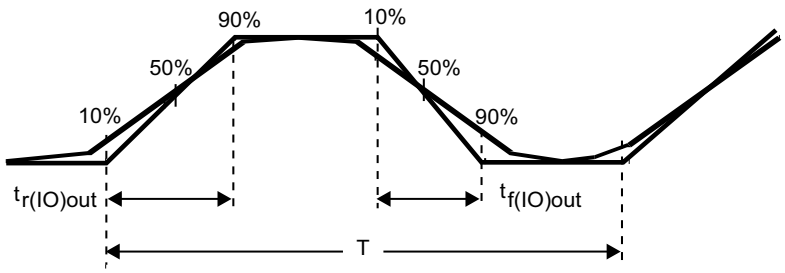
Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

Figure 17. I/O AC characteristics definition



Maximum frequency is achieved if $(t_r + t_f) \leq \frac{2}{3}T$ and if the duty cycle is (45-55%)
when loaded by C_L (see the table *I/O AC characteristics definition*)

MS32132V3

6.3.15 NRST pin characteristics

The NRST pin input driver uses the CMOS technology. It is connected to a permanent pull-up resistor, R_{PU}.

Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 20: General operating conditions*.

Table 48. NRST pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}$	NRST input low level voltage	-	-	-	$0.3\ V_{DD}+0.07^{(1)}$	V
$V_{IH(NRST)}$	NRST input high level voltage	-	$0.445\ V_{DD}+0.398^{(1)}$	-	-	
$V_{hys(NRST)}$	NRST Schmitt trigger voltage hysteresis	-	-	200	-	mV
R_{PU}	Weak pull-up equivalent resistor(2)	$V_{IN} = V_{SS}$	25	40	55	kΩ
$V_{F(NRST)}$	NRST input filtered pulse	-	-	-	$100^{(1)}$	ns
$V_{NF(NRST)}$	NRST input not filtered pulse	$2.7 < V_{DD} < 3.6$	$300^{(3)}$	-	-	ns
		$2.4 < V_{DD} < 3.6$	$500^{(3)}$	-	-	

1. Data based on design simulation only. Not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).
3. Data based on design simulation only. Not tested in production.

Table 50. R_{AIN} max for f_{ADC} = 14 MHz

T_s (cycles)	t_S (µs)	R_{AIN} max (kΩ)(1)
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4
28.5	2.04	25.2
41.5	2.96	37.2
55.5	3.96	50
71.5	5.11	NA
239.5	17.1	NA

1. Guaranteed by design, not tested in production.

Table 51. ADC accuracy(1)(2)(3)

Symbol	Parameter	Test conditions	Typ	Max(4)	Unit
ET	Total unadjusted error	f_{PCLK} = 48 MHz, f_{ADC} = 14 MHz, R_{AIN} < 10 kΩ V_{DDA} = 2.7 V to 3.6 V T_A = -40 to 85 °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	

1. ADC DC accuracy values are measured after internal calibration.
2. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any of the standard (non-robust) analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current.
   Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 6.3.14* does not affect the ADC accuracy.
3. Better performance may be achieved in restricted V_{DDA}, frequency and temperature ranges.
4. Data based on characterization results, not tested in production.

Figure 21. SPI timing diagram - slave mode and CPHA = 0

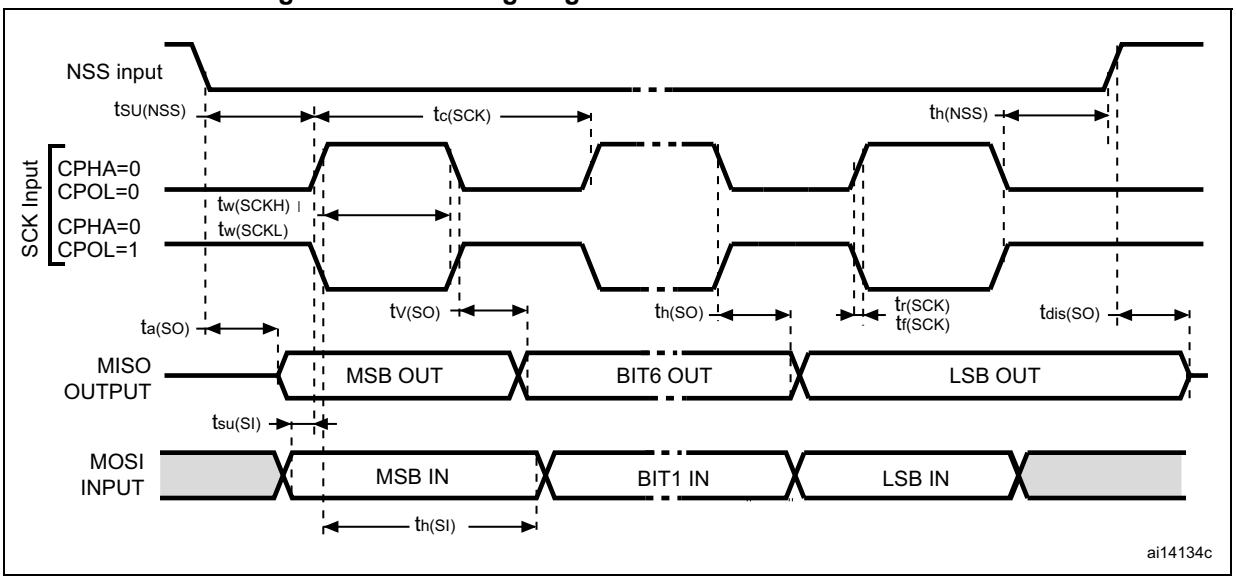
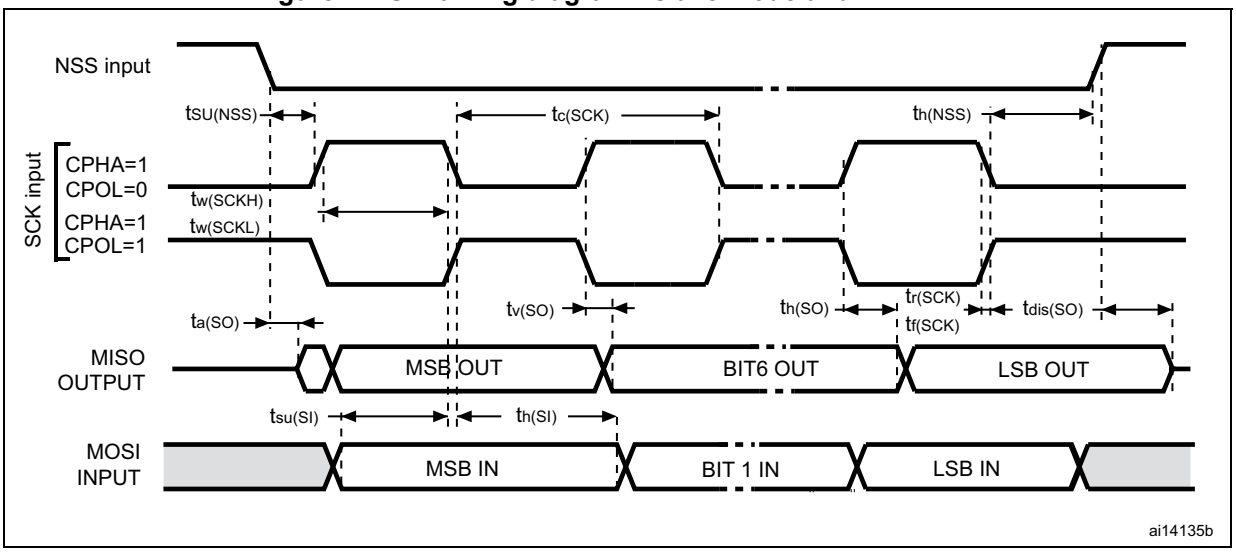


Figure 22. SPI timing diagram - slave mode and CPHA = 1



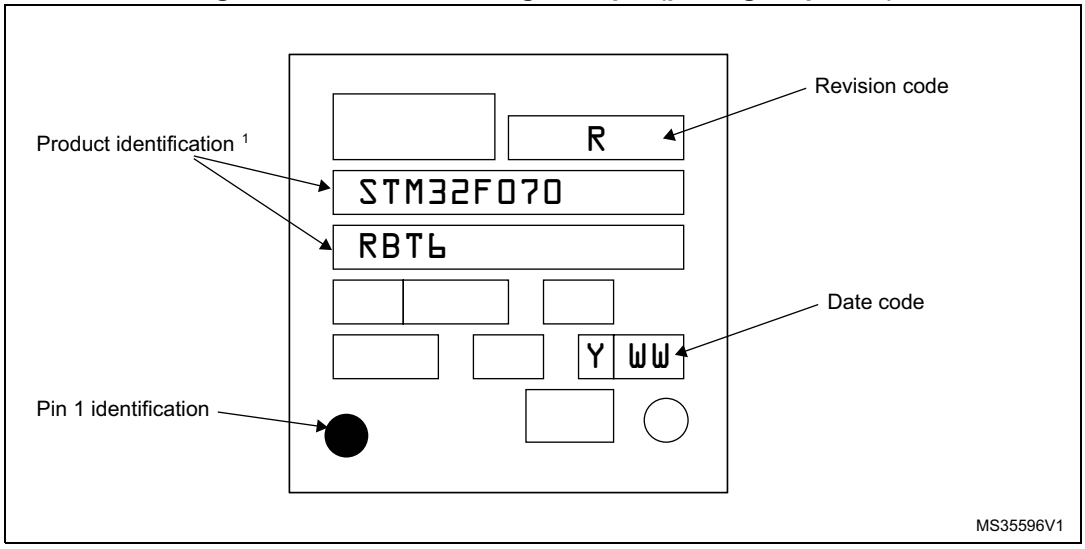
1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 26. LQFP64 marking example (package top view)



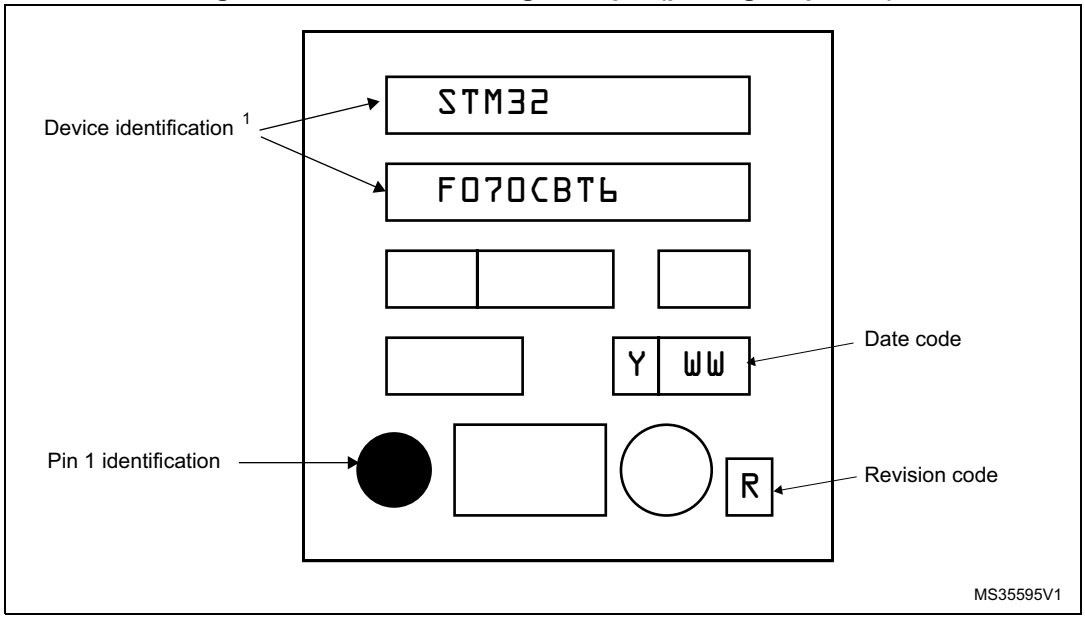
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 29. LQFP48 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

8 Ordering information

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Table 63. Ordering information scheme

Example: STM32 F 070 C 6 T 6 x

Device family

STM32 = ARM-based 32-bit microcontroller

Product type

F = General-purpose

Sub-family

070 = STM32F070xx

Pin count

F = 20 pins

C = 48 pins

R = 64 pins

Code size

6 = 32 Kbyte of Flash memory

B = 128 Kbyte of Flash memory

Package

P = TSSOP

T = LQFP

Temperature range

6 = –40 to 85 °C

Options

xxx = programmed parts

TR = tape and reel

9 Revision history

Table 64. Document revision history

Date	Revision	Changes
27-Nov-2014	1	Initial release.
15-Jan-2015	2	Updated the number of SPI in *Features* and *Section: Description*. Updated *Section: Serial peripheral interface (SPI)*. Updated the fourth footnote of *Table: STM32F070xB/i pin definitions*, and added the reference to PB9 pin. Moved the AF3 data to AF4 for PA9 and PA10 pins in *Table: Alternate functions selected through GPIOA_AFR registers for port A*. Added the reference to footnote 1 to AF0 data for PB12, PB13, PB14 and PB15, and to AF5 data for PB9 and PB10 in *Table: Alternate functions selected through GPIOB_AFR registers for port B*. Added the reference to footnote 1 to SPI2 in *Table: STM32F070xB/6 peripheral register boundary addressesF070.*
07-Feb-2016	3	Updated: – Removal of Table 1 from cover page (all part numbers put in the header) – *Table 1: STM32F070CB/RB/C6/F6 family device features and peripheral counts*; number of int. ADC channels corrected – *Figure 1: Block diagram* – *Figure 2: Clock tree* – *Table 7: STM32F70x0 USART implementation* – *Figure 6: STM32F070CB/RB/C6/F6 memory map* and added the note related to the start address of the system memory – *Figure 9: Power supply scheme* – *Section 3.5.1: Power supply schemes* – *Section 3.11: Timers and watchdogs* - number of complementary outputs in the table – *Table 10: STM32F070xB/6 pin definitions* - TSSOP20 pinout correction, pins 10, 15 and 16 – *Table 23: Embedded internal reference voltage*: added t_{START}, changed V_{REFINT} and $t_{S\_vrefint}$ values and notes – *Table 33: LSE oscillator characteristics (f_{LSE} = 32.768 kHz)* LSEDRV[1:0] values removed (see ref. manual) – *Table 49: ADC characteristics* - t_{STAB} defined relative to clock frequency; notes *3.* and *4.* added – *Table 52: TS characteristics*: removed the min. value for t_{START}